







**MAX3243E** 

SLLS657E - APRIL 2005 - REVISED OCTOBER 2022

# MAX3243E 3-V to 5.5-V Multichannel RS-232 Line Driver/Receiver With ±15-kV IEC ESD Protection

#### 1 Features

- Single-chip and single-supply interface for IBM™ PC/AT™ serial port
- ESD Protection for RS-232 bus pins
  - ±15-kV Human-body model (HBM)
  - ±8-kV IEC61000-4-2, contact discharge
  - ±15-kV IEC61000-4-2, air-gap discharge
- Meets or exceeds requirements of TIA/EIA-232-F and ITU V.28 standards
- Operates with 3-V to 5.5-V  $V_{CC}$  supply
- Always-active noninverting receiver output (ROUT2B)
- Designed to transmit at a data rate up to 500 kbit/s
- Low standby current: 1 µA typical
- External capacitors: 4 × 0.1 µF
- Accepts 5-V logic input with 3.3-V supply
- Designed to Be interchangeable with maxim MAX3243E
- Serial-Mouse Driveability
- Auto-powerdown feature to disable driver outputs when no valid RS-232 signal is sensed
- Package options include plastic small-outline (DW), shrink small-outline (DB), and thin shrink small-outline (PW) packages

# 2 Applications

- Battery powered systems
- Wired Networking
- Data center and enterprise computing
- **Battery-powered systems**
- **Notebooks**
- Laptops
- Palmtop PCs
- Hand-held equipment

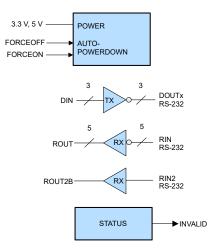
# 3 Description

The MAX3243E device consists of three line drivers. five line receivers, and a dual charge-pump circuit with ±15-kV ESD (HBM and IEC61000-4-2, Air-Gap Discharge) and ±8-kV ESD (IEC61000-4-2, Contact Discharge) protection on serial-port connection pins. The device meets the requirements of TIA/ EIA-232-F and provides the electrical interface between an asynchronous communication controller and the serial-port connector. This combination of drivers and receivers matches that needed for the typical serial port used in an IBM PC/AT, or compatible. The charge pump and four small external capacitors allow operation from a single 3-V to 5.5-V supply. In addition, the device includes an alwaysactive noninverting output (ROUT2B), which allows applications using the ring indicator to transmit data while the device is powered down.

#### Package Information

PART NUMBER	PACKAGE <sup>(1)</sup>	BODY SIZE (NOM)				
	SSOP (DB) (28)	10,20 mm × 5,30 mm				
MAX3243E	SOIC (DW) (28)	17,90 mm × 7,50 mm				
WAX3243E	TSSOP (PW) (28)	9,70 mm × 4,40 mm				
	VQFN (RHB) (32)	5,00 mm × 5,00 mm				

For all available packages, see the orderable addendum at the end of the data sheet.



Simplified Circuit



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# **4 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	Changes from Revision D (September 2011) to Revision E (October 2022)	Page
	Added Device Information table, ESD Ratings, ESD Ratings - IEC Specifications, Thermal Infor Detailed Description, Power Supply Recommendations, Layout, Device and Documentation Supplementation, Policies of Ordering Information tables.	<i>pport</i> 1
	Deleted Ordering Information table	
	Changed the I <sub>CC</sub> Supply current auto-powerdown disabled MAX value from 1 mA to 1.2 mA in the Characteristics	he <i>Electrical</i>
С	Changes from Revision C (February 2009) to Revision D (September 2011)	Page
•	Deleted "VALID RIN RS-232 LEVEL" from INPUTS	13
•	Deleted "ROUT2B is active" RECEIVER STATUS and combined ROUT outputs	13

# 5 Description (continued)

The device operates at data signaling rates up to 250 kbit/s and a maximum of 30-V/µs driver output slew rate.

The MAX3243EC device is characterized for operation from  $0^{\circ}$ C to  $70^{\circ}$ C. The MAX3243EI device is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.



# **6 Pin Configuration and Functions**

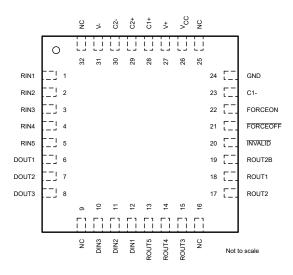


Figure 6-1. RHB Package, 32 Pin (VQFN), Top View

**Table 6-1. Pin Functions** 

PIN TYPE		-V	2-22-1
NO.	NAME	TYPE	DESCRIPTION
1	RIN1		
2	RIN2		
3	RIN3	ı	RS-232 receiver inputs
4	RIN4		
5	RIN5		
6	DOUT1		
7	DOUT2	0	RS-232 driver outputs
8	DOUT3		
9	NC	_	Not connected internally
10	DIN3		
11	DIN2	ı	Driver inputs
12	DIN1		
13	ROUT5		
14	ROUT4	0	Receiver outputs
15	ROUT3		
16	NC	_	Not connected internally
17	ROUT2	0	Passing autoute
18	ROUT1		Receiver outputs
19	ROUT2B	0	Always-active noninverting receiver output
20	INVALID	0	Invalid Output Pin
21	FORCEOFF	1	Auto Powerdown Control input (Refer to Truth Table)
22	FORCEON	1	Auto Powerdown Control input (Refer to Truth Table)
23	C1-	_	Negative terminal of the voltage-doubler charge-pump capacitor
24	GND	_	Ground
25	NC	_	Not connected internally
26	V <sub>CC</sub>	_	3-V to 5.5-V supply voltage



# **Table 6-1. Pin Functions (continued)**

PIN		TYPE	DESCRIPTION	
NO.	NAME	IIFE	DESCRIPTION	
27	V+	_	Positive charge pump output voltage	
28	C1+	_	Positive terminals of the voltage-doubler charge-pump capacitors	
29	C2+	_	r ositive terminals of the voltage-doubler charge-pump capacitors	
30	C2-	_	Negative terminal of the voltage-doubler charge-pump capacitor	
31	V-	_	Negative charge pump output voltage	
32	NC	_	Not connected internally	



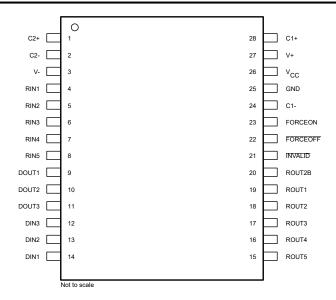


Figure 6-2. DB, DW, or PW Package, 28 Pin (SSOP, SOIC, TSSOP), Top View

**Table 6-2. Pin Functions** 

PIN		TVDE	DESCRIPTION
NO.	NAME	IYPE	DESCRIPTION
1	C2+	_	Positive terminal of the voltage-doubler charge-pump capacitor
2	C2-	_	Negative terminal of the voltage-doubler charge-pump capacitor
NO.         NAME           1         C2+         —         Positive te           2         C2-         —         Negative to           3         V-         Negative to           4         RIN1         RIN2			Negative charge pump output voltage
4	RIN1		
5	RIN2		
6	RIN3	ı	RS-232 receiver inputs
7	RIN4		
8	RIN5		
9	DOUT1		
10	DOUT2	0	RS-232 driver outputs
11	DOUT3		
12	DIN3		
13	DIN2	ı	Driver inputs
14	DIN1		
15	ROUT5		
16	ROUT4		
17	ROUT3	0	Receiver outputs
18	ROUT2		
19	ROUT1		
20	ROUT2B	_	Always-active noninverting receiver output;
21	INVALID	0	Invalid Output Pin
22	FORCEOFF	I	Auto Powerdown Control input (Refer to Truth Table)
23	FORCEON	I	Auto Powerdown Control input (Refer to Truth Table)
24	C1-	_	Negative terminal of the voltage-doubler charge-pump capacitor
25	GND	_	Ground
26	V <sub>CC</sub>	_	3-V to 5.5-V supply voltage
27	V+	_	Positive charge pump output voltage
28	C1+	_	Positive terminal of the voltage-doubler charge-pump capacitor



# 7 Specifications

# 7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range <sup>(2)</sup>		-0.3	6	V
V+	Positive output supply voltage range <sup>(2)</sup>	sitive output supply voltage range <sup>(2)</sup>		7	V
V-	Negative output supply voltage range <sup>(2)</sup>	Negative output supply voltage range <sup>(2)</sup>		-7	V
V+ – V–	Output supply voltage difference <sup>(2)</sup>			13	V
V	land to the second	Driver ( FORCEOFF, FORCEON)	-0.3	6	V
V <sub>I</sub>	Input voltage range	Receiver	-25	25	V
V-	Output voltage range	Driver	-13.2	13.2	V
Vo	Output voltage range	Receiver ( ĪNVALID)	-0.3	V <sub>CC</sub> + 0.3	V
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## 7.2 ESD Ratings

		VALUE	UNIT
V <sub>(ESD)</sub>	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 DOUT1/2/3, RIN1/2/3/4/5 pins <sup>(1)</sup>	±15,000	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

# 7.3 ESD Ratings - IEC Specifications

				VALUE	UNIT
.,	Electrostatic	IEC 61000-4-2 Contact Discharge (1)	RIN1, RIN2, RIN3, RIN4, RIN5, DOUT1,	±8,000	.,
V (ESD)	discharge	IEC 61000-4-2 Air-gap Discharge (1)	DOUT2 and DOUT3 pins	±15,000	V

For DB, PW and RHB package only: A minimum of 1-μF capacitor between V<sub>CC</sub> and GND is required to meet the specified IEC 61000-4-2 rating.

#### 7.4 Recommended Operating Conditions

# See Figure 10-1 (1)

	rigure 10-1 (1)						
				MIN	NOM	MAX	UNIT
	Supply voltage		V <sub>CC</sub> = 3.3 V	3	3.3	3.6	V
	Supply voltage		V <sub>CC</sub> = 5 V	4.5	5	5.5	
V	V <sub>IH</sub> Driver and control high-level input voltage DIN, FORCEOF	DIN, FORCEOFF, FORCEON	V <sub>CC</sub> = 3.3 V	2			V
V <sub>IH</sub>	Driver and control high-level input voltage	DIN, FORCEOFF, FORCEON	V <sub>CC</sub> = 5 V	2.4			) V
V <sub>IL</sub>	Driver and control low-level input voltage	DIN, FORCEOFF, FORCEON				0.8	V
VI	Driver and control input voltage	DIN, FORCEOFF, FORCEON		0		5.5	V
VI	Receiver input voltage			-25		25	V
_	On exating free air temperature		MAX3243EC	0		70	°C
IA	Operating free-air temperature  MAX3243EI			-40		85	

<sup>(1)</sup> Test conditions are C1–C4 = 0.1  $\mu$ F at V<sub>CC</sub> = 3.3 V  $\pm$  0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at V<sub>CC</sub> = 5 V  $\pm$  0.5 V.

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All voltages are with respect to network GND.



#### 7.5 Thermal Information

	THERMAL METRIC(1)	{DB} (SSOP)	{DW} (SOIC)	{PW} (TSSOP)	{RHB} (VQFN)	UNIT
	THERMAL WETRIC	28 PINS	28 PINS	28 PINS	32 PINS	UNII
$R_{\theta JA}$	Junction-to-ambient thermal resistance	76.1	59.0	70.3	34.1	°C/W
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	35.8	28.8	21.0	25.9	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	37.4	30.3	29.2	14.6	°C/W
ΨЈТ	Junction-to-top characterization parameter	7.4	7.8	1.3	0.5	°C/W
ΨЈВ	Junction-to-board characterization parameter	37.0	30.0	28.8	14.6	°C/W
R <sub>θJC(bot)</sub>	Junction-to-case (bottom) thermal resistance	N/A	N/A	N/A	5.1	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

## 7.6 Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)<sup>(1)</sup> (see Figure 10-1)

	PARA	METER	TEST CONDITIONS	MIN	TYP <sup>(2)</sup>	MAX	UNIT
I <sub>I</sub>	Input leakage current	FORCEOFF, FORCEON			±0.01	±1	μΑ
Icc	Supply current (T <sub>A</sub> = 25°C)	Auto-powerdown disabled	No load, FORCEOFF and FORCEON at V <sub>CC</sub> For DB, PW and RHB package		0.3	1.2	mA
		Auto-powerdown disabled	No load, FORCEOFF and FORCEON at V <sub>CC</sub> For DW package		0.3	1	mA
		Powered off	No load, FORCEOFF at GND		1	10	
		Auto-powerdown enabled	No load, FORCEOFF at V <sub>CC</sub> , FORCEON at GND, All RIN are open or grounded, All DIN are grounded		1	10	μΑ

Test conditions are C1–C4 = 0.1  $\mu$ F at V<sub>CC</sub> = 3.3 V  $\pm$  0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at V<sub>CC</sub> = 5 V  $\pm$  0.5 V. All typical values are at V<sub>CC</sub> = 3.3 V or V<sub>CC</sub> = 5 V, and T<sub>A</sub> = 25°C.

#### 7.7 Driver Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)<sup>(1)</sup> (see Figure 10-1)

	PARAMETER	TES	T CONDITIONS	MIN	TYP <sup>(2)</sup>	MAX	UNIT
V <sub>OH</sub>	High-level output voltage	All DOUT at $R_L = 3 k\Omega$ to 0	GND	5	5.4		V
V <sub>OL</sub>	Low-level output voltage	All DOUT at $R_L = 3 k\Omega$ to 0	GND	-5	-5.4		V
Vo	Output voltage (mouse driveability)	DIN1 = DIN2 = GND, DIN3 = $V_{CC}$ , 3- $k\Omega$ to GND at DOUT3, DOUT1 = DOUT2 = 2.5 mA					٧
I <sub>IH</sub>	High-level input current	V <sub>I</sub> = V <sub>CC</sub>			±0.01	±1	μA
I <sub>IL</sub>	Low-level input current	V <sub>I</sub> at GND			±0.01	±1	μA
V <sub>hys</sub>	Input hysteresis					±1	V
	Short-circuit output current <sup>(3)</sup>	V <sub>CC</sub> = 3.6 V,	V <sub>O</sub> = 0 V			±60	mA
I <sub>OS</sub>	Short-circuit output current	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 0 V			100	IIIA
r <sub>o</sub>	Output resistance	V <sub>CC</sub> , V+, and V- = 0 V,	V <sub>O</sub> = ±2 V	300	10M		Ω
I <sub>off</sub>	Output leakage current	FORCEOFF = GND,	$V_{O} = \pm 12 \text{ V},  V_{CC} = 0 \text{ to } 5.5 \text{ V}$			±25	μΑ

- (1) Test conditions are C1–C4 = 0.1  $\mu$ F at V<sub>CC</sub> = 3.3 V  $\pm$  0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at V<sub>CC</sub> = 5 V  $\pm$  0.5 V.
- (2) All typical values are at  $V_{CC} = 3.3 \text{ V}$  or  $V_{CC} = 5 \text{ V}$ , and  $T_A = 25 ^{\circ}\text{C}$ .
- (3) Short-circuit durations should be controlled to prevent exceeding the device absolute power dissipation ratings, and not more than one output should be shorted at a time.

#### 7.8 Receiver, Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)<sup>(1)</sup> (see Figure 10-1)

	PARAMETER	TEST CONDITIONS	MIN	TYP <sup>(2)</sup>	MAX	UNIT
V <sub>OH</sub>	High-level output voltage	I <sub>OH</sub> = -1 mA	V <sub>CC</sub> - 0.6	V <sub>CC</sub> – 0.1		V
V <sub>OL</sub>	Low-level output voltage	I <sub>OH</sub> = 1.6 mA			0.4	V
V <sub>IT+</sub>	Positive-going input threshold voltage	V <sub>CC</sub> = 3.3 V		1.6	2.4	V
VIT+	T+ Tositive-going input timeshold voltage	V <sub>CC</sub> = 5 V		1.9	2.4	v
V <sub>IT</sub> _	T_ Negative-going input threshold voltage	V <sub>CC</sub> = 3.3 V	0.6	1.1		V
VII-	Negative-going input the should voltage	V <sub>CC</sub> = 5 V	0.8	1.4		v
V <sub>hys</sub>	Input hysteresis (V <sub>IT+</sub> – V <sub>IT-</sub> )			0.5		V
I <sub>off</sub>	Output leakage current (except ROUT2B)	FORCEOFF = 0 V		±0.05	±10	μΑ
r <sub>i</sub>	Input resistance	V <sub>I</sub> = ±3 V or ±25 V	3	5	7	kΩ

- (1) Test conditions are C1–C4 = 0.1  $\mu$ F at  $V_{CC}$  = 3.3 V  $\pm$  0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at  $V_{CC}$  = 5 V  $\pm$  0.5 V.
- (2) All typical values are at  $V_{CC} = 3.3 \text{ V}$  or  $V_{CC} = 5 \text{ V}$ , and  $T_A = 25 ^{\circ}\text{C}$ .

#### 7.9 Auto-Powerdown Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 8-5)

	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
V <sub>IT+(valid)</sub>	Receiver input threshold for INVALID high-level output voltage	FORCEON = GND, FORCEOFF = V <sub>CC</sub>		2.7	V
V <sub>IT-(valid)</sub>	Receiver input threshold for INVALID high-level output voltage	FORCEON = GND, FORCEOFF = V <sub>CC</sub>	-2.7		V
V <sub>T(invalid)</sub>	Receiver input threshold for INVALID low-level output voltage	FORCEON = GND, FORCEOFF = V <sub>CC</sub>	-0.3	0.3	V
V <sub>OH</sub>	INVALID high-level output voltage	I <sub>OH</sub> = -1 mA, FORCEON = GND, FORCEOFF = V <sub>CC</sub>	V <sub>CC</sub> - 0.6		V
V <sub>OL</sub>	INVALID low-level output voltage	I <sub>OL</sub> = 1.6 mA, FORCEON = GND, FORCEOFF = V <sub>CC</sub>		0.4	V

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## 7.10 Driver Switching Characteristics

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)<sup>(1)</sup> (see Figure 10-1)

,	(333 : 1931 - 13 : 1)						
	PARAMETER	TEST C	TEST CONDITIONS				
	Maximum data rate	C <sub>L</sub> = 1000 pF, One DOUT switching,	R <sub>L</sub> = 3 kΩ See Figure 8-1	250	500		kbit/s
t <sub>sk(p)</sub>	Pulse skew <sup>(3)</sup>	C <sub>L</sub> = 150 pF to 2500 pF,	$R_L$ = 3 kΩ to 7 kΩ, See Figure 8-2		100		ns
25"	Slew rate, transition region	V <sub>CC</sub> = 3.3 V,	C <sub>L</sub> = 150 pF to 1000 pF	6		30	
SR(tr) (see Figure 8-1)		$R_L$ = 3 kΩ to 7 kΩ, PRR = 250 kbit/s	C <sub>L</sub> = 150 pF to 2500 pF	4		30	V/µs

- (1) Test conditions are C1–C4 = 0.1  $\mu$ F at  $V_{CC}$  = 3.3 V + 0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at  $V_{CC}$  = 5 V ± 0.5 V.
- (2) All typical values are at  $V_{CC}$  = 3.3 V or  $V_{CC}$  = 5 V, and  $T_A$  = 25°C.
- (3) Pulse skew is defined as |t<sub>PLH</sub> t<sub>PHL</sub>| of each channel of the same device.

### 7.11 Receiver Switching Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)<sup>(1)</sup>

	PARAMETER	TEST CONDITIONS	TYP <sup>(2)</sup>	UNIT
t <sub>PLH</sub>	Propagation delay time, low- to high-level output	C <sub>L</sub> = 150 pF, See Figure 8-3	150	ns
t <sub>PHL</sub>	Propagation delay time, high- to low-level output		150	ns
t <sub>en</sub>	Output enable time	$C_L$ = 150 pF, $R_L$ = 3 k $\Omega$ , See Figure 8-4	200	ns
t <sub>dis</sub>	Output disable time		200	ns
t <sub>sk(p)</sub>	Puse skew <sup>(3)</sup>	See Figure 8-3	50	ns

- (1) Test conditions are C1–C4 = 0.1  $\mu$ F at  $V_{CC}$  = 3.3 V ± 0.3 V; C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F at  $V_{CC}$  = 5 V ± 0.5 V.
- (2) All typical values are at  $V_{CC} = 3.3 \text{ V}$  or  $V_{CC} = 5 \text{ V}$ , and  $T_A = 25 ^{\circ}\text{C}$ .
- (3) Pulse skew is defined as |t<sub>PLH</sub> t<sub>PHL</sub>| of each channel of the same device.

## 7.12 Auto-Powerdown Switching Characteristics

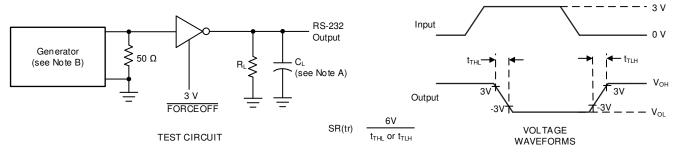
over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 8-5)

	PARAMETER	TEST CONDITIONS	TYP <sup>(1)</sup>	UNIT
t <sub>valid</sub>	Propagation delay time, low- to high-level output	V <sub>CC</sub> = 5 V	1	μs
t <sub>invalid</sub>	Propagation delay time, high- to low-level output	V <sub>CC</sub> = 5 V	30	μs
t <sub>en</sub>	Supply enable time	V <sub>CC</sub> = 5 V	100	μs

(1) All typical values are at  $V_{CC}$  = 3.3 V or  $V_{CC}$  = 5 V, and  $T_A$  = 25°C.

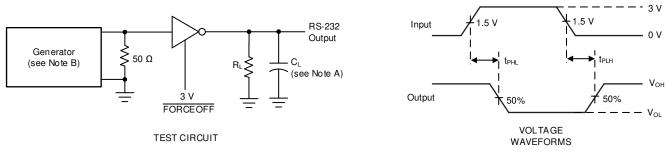


### **8 Parameter Measurement Information**



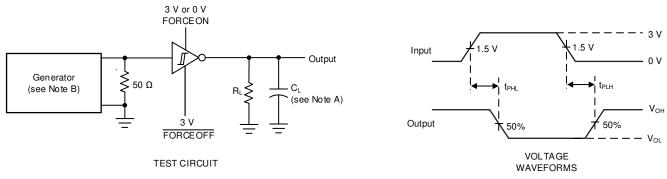
- A. C<sub>L</sub> includes probe and jig capacitance
- B. The pulse generator has the following characteristics: PRR = 5 kbit/s,  $Z_0 = 50 \Omega$ , 50 % duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

Figure 8-1. Driver Slew Rate



- A. C<sub>L</sub> includes probe and jig capacitance
- B. The pulse generator has the following characteristics: PRR = 5 kbit/s,  $Z_0$  = 50  $\Omega$ , 50 % duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

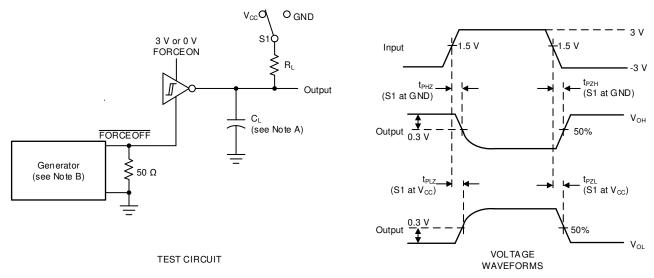
Figure 8-2. Driver Pulse Skew



- C<sub>L</sub> includes probe and jig capacitance
- B. The pulse generator has the following characteristics: PRR = 5 kbit/s,  $Z_0$  = 50  $\Omega$ , 50 % duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

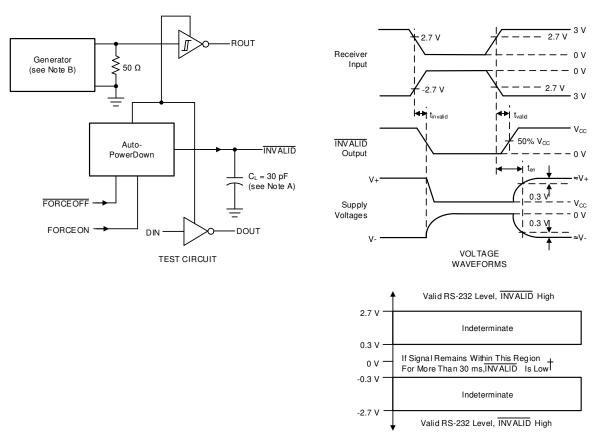
Figure 8-3. Receiver Propagation Delay Times





- A. C<sub>L</sub> includes probe and jig capacitance
- B. The pulse generator has the following characteristics: PRR = 5 kbit/s,  $Z_0$  = 50  $\Omega$ , 50 % duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.
- C.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- D.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .

Figure 8-4. Receiver Enable and Disable Times



- A. C<sub>L</sub> includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: PRR = 5 kbit/s,  $Z_0$  = 50  $\Omega$ , 50 % duty cycle,  $t_r \le 10$  ns.

Figure 8-5. INVALID Propagation Delay Times and Supply Enabling Time

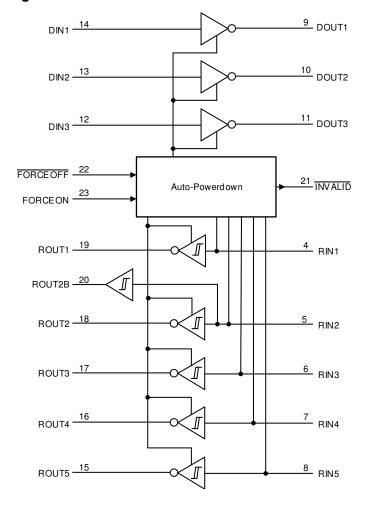
# 9 Detailed Description

## 9.1 Overview

The MAX3243E device consists of three line drivers, five line receivers, and a dual charge-pump circuit with ±15-kV ESD (HBM and IEC61000-4-2, Air-Gap Discharge) and ±8-kV ESD (IEC61000-4-2, Contact Discharge) protection on serial-port connection pins. The device meets the requirements of TIA/EIA-232-F and provides the electrical interface between an asynchronous communication controller and the serial-port connector.

The charge pump and four small external capacitors allow operation from a single 3-V to 5.5-V supply. In addition, the device includes an always-active noninverting output (ROUT2B), which allows applications using the ring indicator to transmit data while the device is powered down. The device operates at data signaling rates up to 250 kbit/s and a maximum of 30-V/µs driver output slew rate.

# 9.2 Functional Block Diagram



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#### 9.3 Feature Description

Flexible control options for power management are available when the serial port is inactive. The autopowerdown feature functions when FORCEON is low and  $\overline{FORCEOFF}$  is high. During this mode of operation, if the device does not sense a valid RS-232 signal, the driver outputs are disabled. If  $\overline{FORCEOFF}$  is set low, both drivers and receivers (except ROUT2B) are shut off, and the supply current is reduced to 1  $\mu$ A. Disconnecting the serial port or turning off the peripheral drivers causes the auto-powerdown condition to occur.

Auto-powerdown can be disabled when FORCEON and  $\overline{\text{FORCEOFF}}$  are high, and should be done when driving a serial mouse. With auto-powerdown enabled, the device is activated automatically when a valid signal is applied to any receiver input. The  $\overline{\text{INVALID}}$  output is used to notify the user if an RS-232 signal is present at any receiver input.  $\overline{\text{INVALID}}$  is high (valid data) if any receiver input voltage is greater than 2.7 V or less than -2.7 V or has been between -0.3 V and 0.3 V for less than 30  $\mu$ s.  $\overline{\text{INVALID}}$  is low (invalid data) if all receiver input voltages are between -0.3 V and 0.3 V for more than 30  $\mu$ s. Refer to Figure 8-5 for receiver input levels.

#### 9.4 Device Functional Modes

Figure 9-1 through 9-3 show the device functional modes.

INPUTS(1) **OUTPUT DRIVER STATUS VALID RIN** FORCEOFF DIN **FORCEON** DOUT RS-232 LEVEL Ζ Χ Х Powered off 1 L Н Н Х Н Normal operation with auto-powerdown disabled Н Н Н Х L L L Н Yes Н Normal operation with auto-powerdown enabled Н L Н Yes L Powered off by auto-powerdown Χ L Н Ζ No feature

Table 9-1. Each Driver

Table 9-2. Each Receiver

INPUTS <sup>(1)</sup>		RECEIVER STATUS			
RIN	FORCEON	FORCEOFF	ROUT	RECEIVER STATUS	
X	X	L	Z	Powered off	
L	X	Н	Н		
Н	X	Н	L	Normal operation with auto-powerdown disabled/enabled	
Open	X	Н	Н	date pewerdenn diedbied/endbied	

(1) H = high level, L = low level, X = irrelevant, Z = high impedance (off), Open = input disconnected or connected driver off

Table 9-3. Outputs ROUT2B and INVALID

INPUTS <sup>(1)</sup>			OUTPUTS				
VALID RIN RS-232 LEVEL	PIN2 FORCEON FORCEOFF INVALID POLITOR		OUTPUT STATUS				
Yes	L	Х	Х	Н	L		
Yes	Н	X	X	Н	Н	Alwaya activo	
Yes	Open	X	X	Н	L	Always active	
No	Open	X	X	L	L		

(1) H = high level, L = low level, X = irrelevant, Z = high impedance (off), Open = input disconnected or connected driver off

# 10 Application and Implementation

#### **Note**

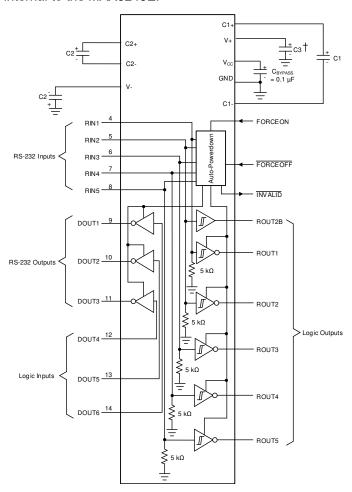
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

## 10.1 Application Information

For proper operation, add capacitors as shown in Figure 10-1. Pins 12 through 23 connect to UART or general purpose logic lines. RS-232 lines on Pins 4 through 11 connect to a connector or cable.

# 10.2 Typical Application

Three driver and five receiver channels are supported for full duplex transmission with hardware flow control. The five 5-k $\Omega$  resistors are internal to the MAX3243E.



- † C3 can be connected to  $V_{\text{CC}}$  or GND
- A. Resistor values shown are nominal.
- B. Nonpolarized ceramic capacitors are acceptable. If polarized tantalum or electrolytic capacitors are used, they should be connected as shown.

Figure 10-1. Typical Operating Circuit and Capacitor Values

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#### 10.2.1 Design Requirements

For this design example, use the values in Table 10-1.

- V<sub>CC</sub> minimum is 3 V and maximum is 5.5 V.
- Maximum recommended bit rate is 250 kbps.

Table 10	)-1.	$V_{CC}$	vs	Capacitor	<b>Values</b>
----------	------	----------	----	-----------	---------------

V <sub>CC</sub>	C1	C2, C3, and C4
3.3 V ± 0.3 V	0.1 µF	0.1 μF
5 V ± 0.5 V	0.047 μF	0.33 μF
3 V to 5.5 V	0.1 µF	0.47 μF

## 10.2.2 Detailed Design Procedure

MAX3243E has integrated charge-pump that generates positive and negative rails needed for RS-232 signal levels. Main design requirement is that charge-pump capacitor terminals must be connected with recommended capacitor values. Charge-pump rail voltages and device supply pin must be properly bypassed with ceramic capacitors.

#### 10.2.2.1 ESD Protection

TI MAX3243E devices have standard ESD protection structures incorporated on the pins to protect against electrostatic discharges encountered during assembly and handling. In addition, the RS232 bus pins (driver outputs and receiver inputs) of these devices have an extra level of ESD protection. Advanced ESD structures were designed to successfully protect these bus pins against ESD discharge of ±15-kV in all states: normal operation, shutdown, and powered down. The MAX3243E devices are designed to continue functioning properly after an ESD occurrence without any latchup.

The MAX3243E devices have three specified ESD limits on the driver outputs and receiver inputs, with respect to GND:

- ±15-kV Human Body Model (HBM)
- ±15-kV IEC61000-4-2, Air-Gap Discharge (formerly IEC1000-4-2)
- ±8-kV IEC61000-4-2, Contact Discharge

#### 10.2.2.1.1 ESD Test Conditions

ESD testing is stringently performed by TI, based on various conditions and procedures. Please contact TI for a reliability report that documents test setup, methodology, and results.

#### 10.2.2.1.2 Human Body Model (HBM)

The Human Body Model of ESD testing is shown in Figure 10-2, while Figure 10-3 shows the current waveform that is generated during a discharge into a low impedance. The model consists of a 100-pF capacitor, charged to the ESD voltage of concern, and subsequently discharged into the DUT through a  $1.5k-\Omega$  resistor.

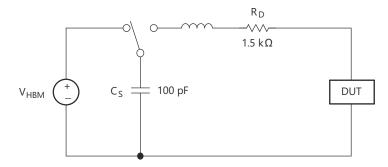


Figure 10-2. HBM ESD Test Circuit



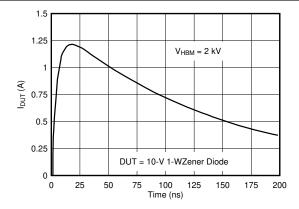


Figure 10-3. Typical HBM Current Waveform

#### 10.2.2.1.3 IEC61000-4-2 (Formerly Known as IEC1000-4-2)

Unlike the HBM, MM, and CDM, ESD tests that apply to component level integrated circuits, the IEC61000-4-2 is a system-level ESD testing and performance standard that pertains to the end equipment. The MAX3243E device is designed to enable the manufacturer in meeting the highest level (Level 4) of IEC61000-4-2 ESD protection with no further need of external ESD protection circuitry. The more stringent IEC test standard has a higher peak current than the HBM, due to the lower series resistance in the IEC model.

Figure 10-4 shows the IEC61000-4-2 model, and Figure 10-5 shows the current waveform for the corresponding ±8-kV Contact-Discharge (Level 4) test. This waveform is applied to a probe that has been connected to the DUT. On the other hand, the corresponding ±15-kV (Level 4) Air-Gap Discharge test involves approaching the DUT with an already energized probe.

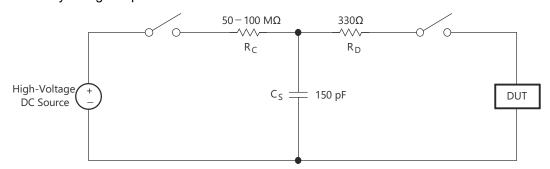


Figure 10-4. Simplified IEC61000-4-2 ESD Test Circuit

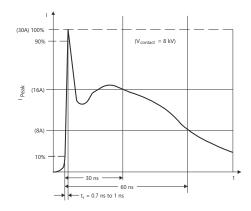


Figure 10-5. Typical Current Waveform of IEC61000-4-2 ESD Generator

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#### 10.2.2.1.4 Machine Model

The Machine Model (MM) ESD test applies to all pins using a 200-pF capacitor with no discharge resistance. The purpose of the MM test is to simulate possible ESD conditions that can occur during the handling and assembly processes of manufacturing. In this case, ESD protection is required for all pins, not just RS-232 pins. However, after PC board assembly, the MM test is no longer as pertinent to the RS-232 pins.

## 10.3 Power Supply Recommendations

The  $V_{CC}$  voltage must be connected to the same power source used for logic device connected to DIN and ROUT pins.  $V_{CC}$  must be between 3 V and 5.5 V.

### 10.4 Layout

As shown in Layout Example, charge-pump and supply voltage capacitors must be located very close to device pins. Non-polarized ceramic capacitors are recommended. If polarized tantalum or electrolytic capacitors are used, they should be connected as per Typical Operating Circuit and Capacitor Values.

#### 10.4.1 Layout Example

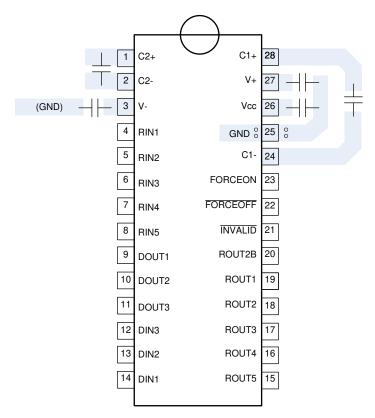


Figure 10-6. Example Layout



# **Device and Documentation Support**

# 11.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 11.2 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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#### 11.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 11.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

## 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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# **PACKAGING INFORMATION**

Orderable part number	Status (1)	Material type	Package   Pins	Package qty   Carrier	<b>RoHS</b> (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
MAX3243ECDB	Obsolete	Production	SSOP (DB)   28	-	-	Call TI	Call TI	0 to 70	MAX3243EC
MAX3243ECDBR	Active	Production	SSOP (DB)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3243EC
MAX3243ECDBR.A	Active	Production	SSOP (DB)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3243EC
MAX3243ECDW	Obsolete	Production	SOIC (DW)   28	-	-	Call TI	Call TI	0 to 70	MAX3243EC
MAX3243ECDWR	Active	Production	SOIC (DW)   28	1000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3243EC
MAX3243ECDWR.A	Active	Production	SOIC (DW)   28	1000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	MAX3243EC
MAX3243ECPWR	Active	Production	TSSOP (PW)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	MP243EC
MAX3243ECPWR.A	Active	Production	TSSOP (PW)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	MP243EC
MAX3243ECPWRG4	Active	Production	TSSOP (PW)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	MP243EC
MAX3243ECRHBR	Active	Production	VQFN (RHB)   32	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	0 to 70	MP243E
MAX3243ECRHBR.A	Active	Production	VQFN (RHB)   32	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	0 to 70	MP243E
MAX3243ECRHBRG4	Active	Production	VQFN (RHB)   32	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MP243E
MAX3243ECRHBRG4.A	Active	Production	VQFN (RHB)   32	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MP243E
MAX3243EIDBR	Active	Production	SSOP (DB)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3243EI
MAX3243EIDBR.A	Active	Production	SSOP (DB)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3243EI
MAX3243EIDBRG4	Active	Production	SSOP (DB)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3243EI
MAX3243EIDBRG4.A	Active	Production	SSOP (DB)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3243EI
MAX3243EIDW	Obsolete	Production	SOIC (DW)   28	-	-	Call TI	Call TI	-40 to 85	MAX3243EI
MAX3243EIDWR	Active	Production	SOIC (DW)   28	1000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3243EI
MAX3243EIDWR.A	Active	Production	SOIC (DW)   28	1000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3243EI
MAX3243EIDWRG4	Active	Production	SOIC (DW)   28	1000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MAX3243EI
MAX3243EIPWR	Active	Production	TSSOP (PW)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MP243EI
MAX3243EIPWR.A	Active	Production	TSSOP (PW)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MP243EI
MAX3243EIPWRE4	Active	Production	TSSOP (PW)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MP243EI
MAX3243EIPWRG4	Active	Production	TSSOP (PW)   28	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MP243EI
MAX3243EIRHBR	Active	Production	VQFN (RHB)   32	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MR243E
MAX3243EIRHBR.A	Active	Production	VQFN (RHB)   32	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MR243E
MAX3243EIRHBRG4	Active	Production	VQFN (RHB)   32	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MR243E

# PACKAGE OPTION ADDENDUM

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- (1) Status: For more details on status, see our product life cycle.
- (2) Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.
- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

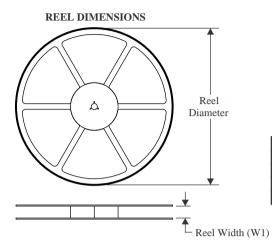
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## TAPE AND REEL INFORMATION



# TAPE DIMENSIONS + K0 - P1 - B0 W Cavity - A0 -

A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

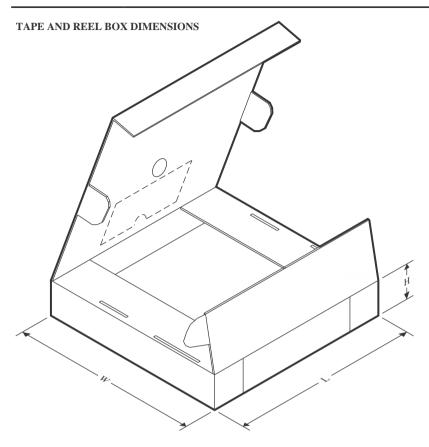


#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
MAX3243ECDBR	SSOP	DB	28	2000	330.0	16.4	8.45	10.55	2.5	12.0	16.2	Q1
MAX3243ECDWR	SOIC	DW	28	1000	330.0	32.4	11.35	18.67	3.1	16.0	32.0	Q1
MAX3243ECPWR	TSSOP	PW	28	2000	330.0	16.4	6.75	10.1	1.8	12.0	16.0	Q1
MAX3243ECRHBR	VQFN	RHB	32	3000	330.0	12.4	5.3	5.3	1.1	8.0	12.0	Q2
MAX3243ECRHBRG4	VQFN	RHB	32	3000	330.0	12.4	5.3	5.3	1.1	8.0	12.0	Q2
MAX3243EIDBR	SSOP	DB	28	2000	330.0	16.4	8.45	10.55	2.5	12.0	16.2	Q1
MAX3243EIDBRG4	SSOP	DB	28	2000	330.0	16.4	8.45	10.55	2.5	12.0	16.2	Q1
MAX3243EIDWR	SOIC	DW	28	1000	330.0	32.4	11.35	18.67	3.1	16.0	32.0	Q1
MAX3243EIPWR	TSSOP	PW	28	2000	330.0	16.4	6.75	10.1	1.8	12.0	16.0	Q1
MAX3243EIRHBR	VQFN	RHB	32	3000	330.0	12.4	5.3	5.3	1.1	8.0	12.0	Q2



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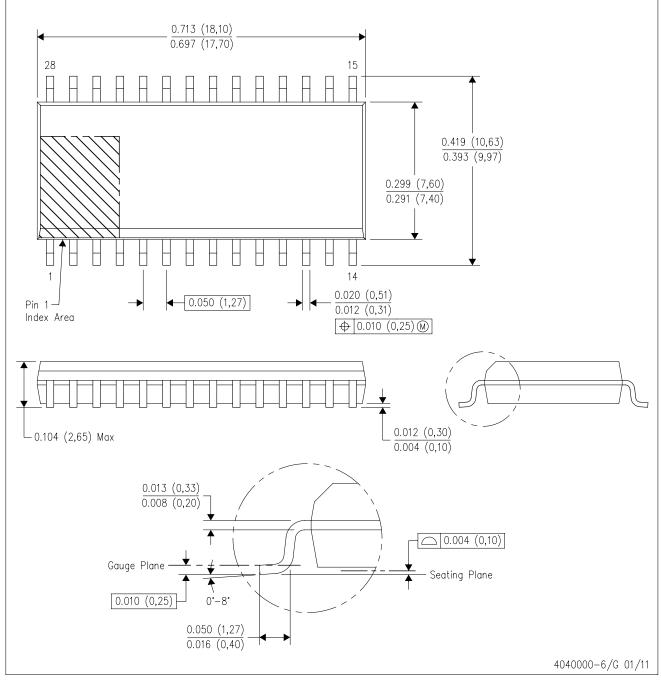


\*All dimensions are nominal

7 til dilitiononono di o momina								
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
MAX3243ECDBR	SSOP	DB	28	2000	353.0	353.0	32.0	
MAX3243ECDWR	SOIC	DW	28	1000	350.0	350.0	66.0	
MAX3243ECPWR	TSSOP	PW	28	2000	353.0	353.0	32.0	
MAX3243ECRHBR	VQFN	RHB	32	3000	367.0	367.0	35.0	
MAX3243ECRHBRG4	VQFN	RHB	32	3000	367.0	367.0	35.0	
MAX3243EIDBR	SSOP	DB	28	2000	353.0	353.0	32.0	
MAX3243EIDBRG4	SSOP	DB	28	2000	353.0	353.0	32.0	
MAX3243EIDWR	SOIC	DW	28	1000	350.0	350.0	66.0	
MAX3243EIPWR	TSSOP	PW	28	2000	353.0	353.0	32.0	
MAX3243EIRHBR	VQFN	RHB	32	3000	367.0	367.0	35.0	

DW (R-PDSO-G28)

# PLASTIC SMALL OUTLINE



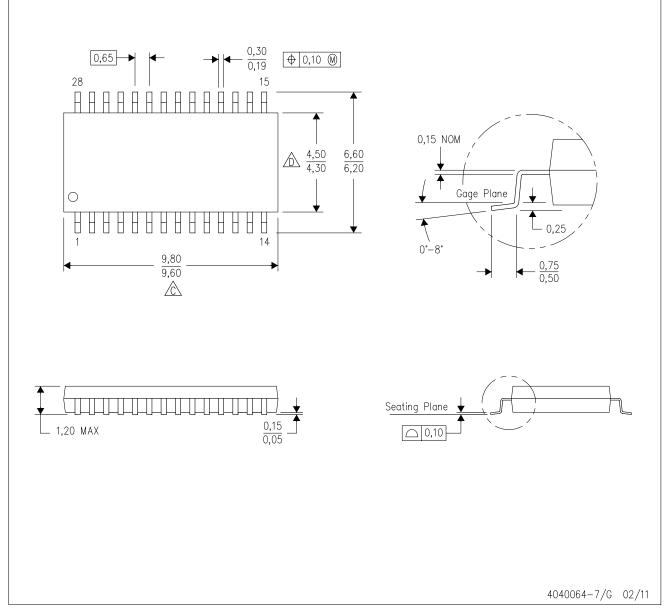
NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AE.



PW (R-PDSO-G28)

# PLASTIC SMALL OUTLINE



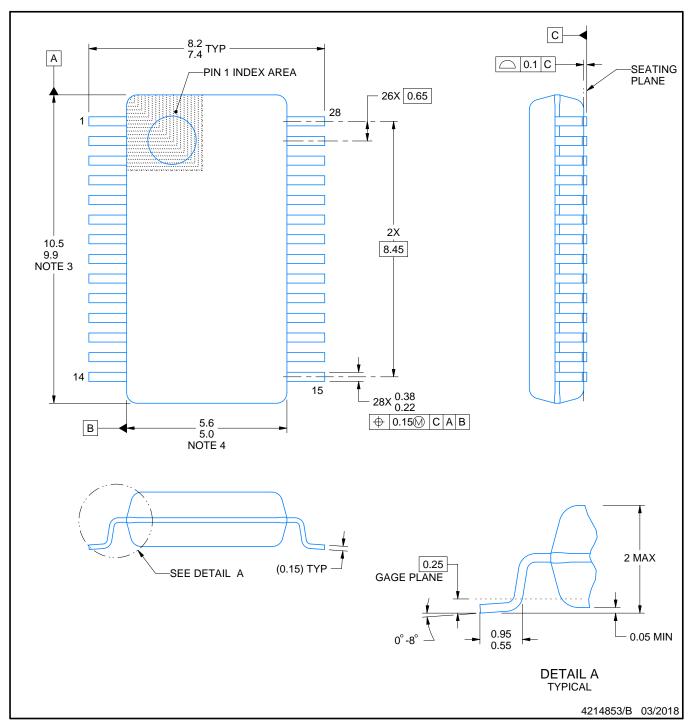
NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153





SMALL OUTLINE PACKAGE



#### NOTES:

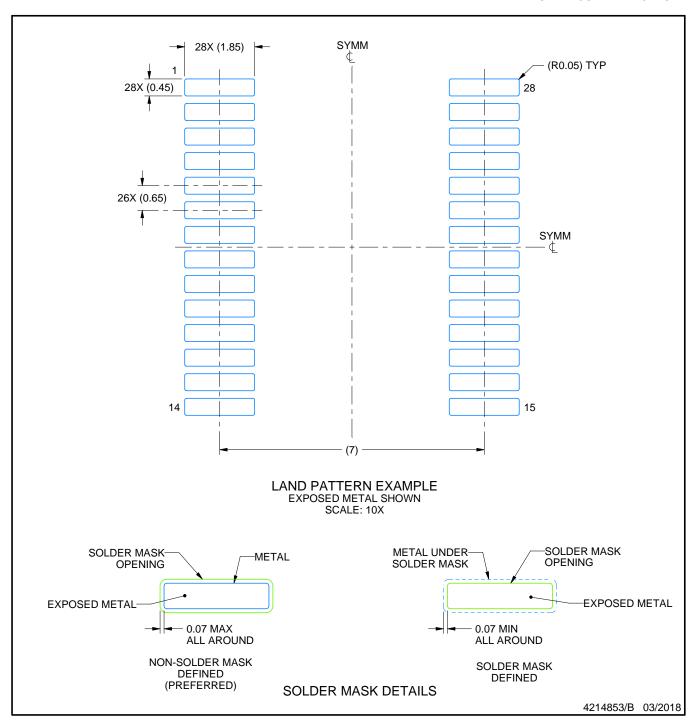
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-150.



SMALL OUTLINE PACKAGE



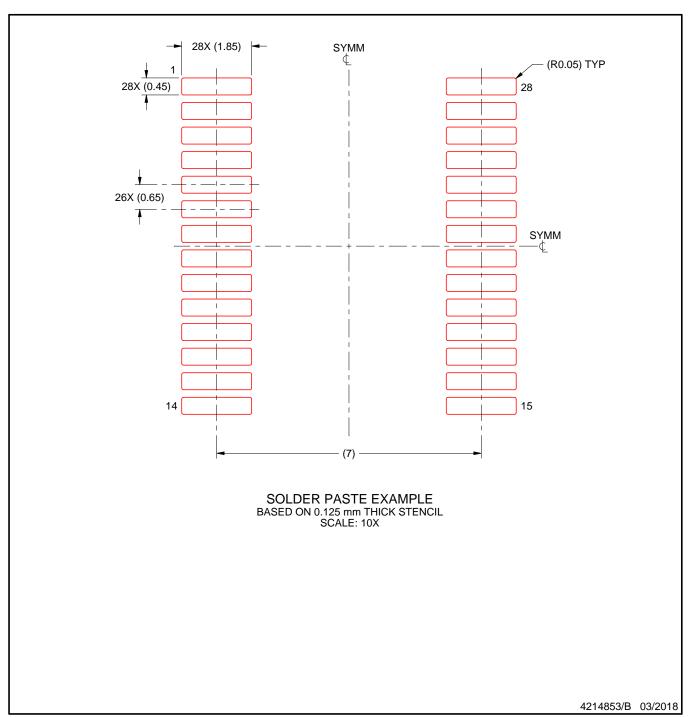
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



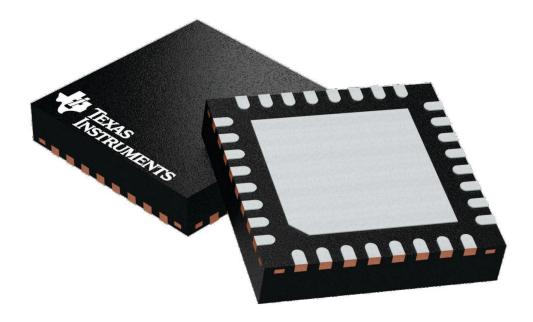
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



5 x 5, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD



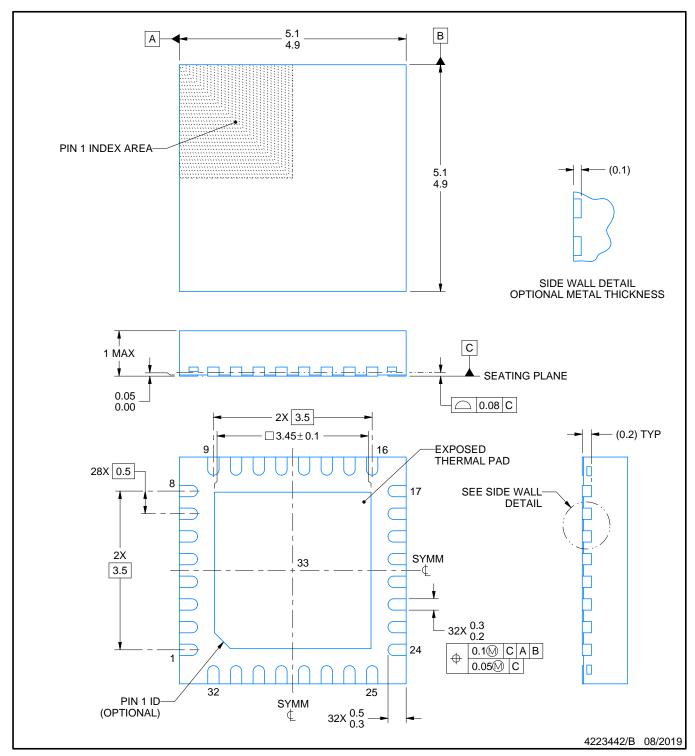
Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4224745/A





PLASTIC QUAD FLATPACK - NO LEAD

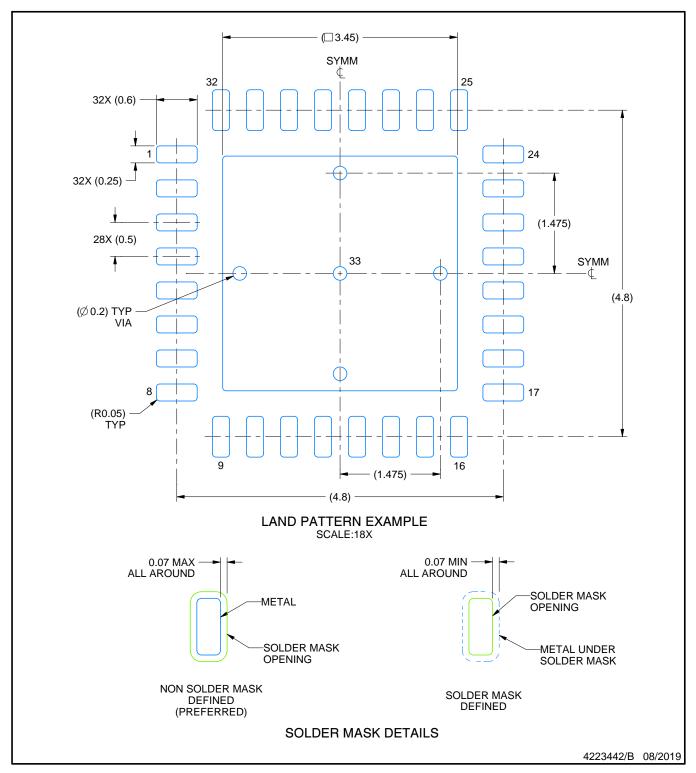


#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
  2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

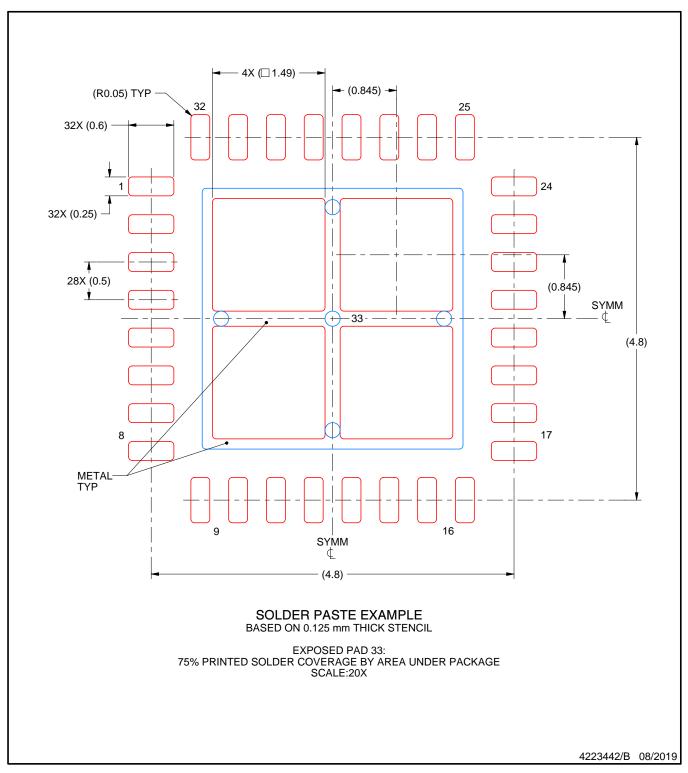


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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